INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)				Docket Number (Optional) OKI.313 Applicant(s) N riyuki MIURA Filing Date		Group Art Unit	NEW E		
March 8, 2002 Unknown U.S. PATENT DOCUMENTS									
*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING IF APPRO		
								FRIATE	
					ļ			-	
		\\			ļ				
					ļ				
					-				
					 				
,							<u> </u>		
				FOREIGN PATENT DOCUMENTS				Transletien	
	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	YES	NO	
						_			
					 	-			
	لـــــا					Date, Pertinent Pa			
Jeffrey W. Thomas et al., "Characteristics of Submicrometer LOCOS Isolation", 1995 IEEE International SOI Conference, Oct. 1995, pgs. 116-117.									
		2							
EXAMINE	R	De		DATE CONSIDERED	DATE CONSIDERED NOV-2003				
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.									